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(12) **United States Design Patent**
Mende et al.

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(54) **PROBE HEAD**

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(**) Term: **15 Years**

(21) Appl. No.: **29/856,463**

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(51) **LOC (14) Cl.** **24-02**

(52) **U.S. Cl.**
USPC **D24/187**

(58) **Field of Classification Search**
USPC D24/133, 137, 138, 141, 158, 160, 164,
D24/165, 167, 170, 186, 187, 200;
D10/57, 60, 78, 80

(Continued)

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Primary Examiner — Omeed Agilee

(74) *Attorney, Agent, or Firm* — Diana Mederos; Mederos Legal, PLLC

(57) **CLAIM**

The ornamental design for a probe head, as shown and described.

DESCRIPTION

FIG. 1 is a top view of a probe head according to the present invention;

FIG. 2 is a front view of the probe head of FIG. 1;

FIG. 3 is a left view of the probe head of FIG. 1;

FIG. 4 is a back view of the probe head of FIG. 1;

FIG. 5 is a right view of the probe head of FIG. 1;

FIG. 6 is a bottom view of the probe head FIG. 1;

FIG. 7 is a top-left rear view of the probe head of FIG. 1

FIG. 8 is a top-right rear view of the probe head of FIG. 1.

FIG. 9 is a top-left front view of the probe head of FIG. 1.

FIG. 10 is a top-right front view of the probe head of FIG. 1.

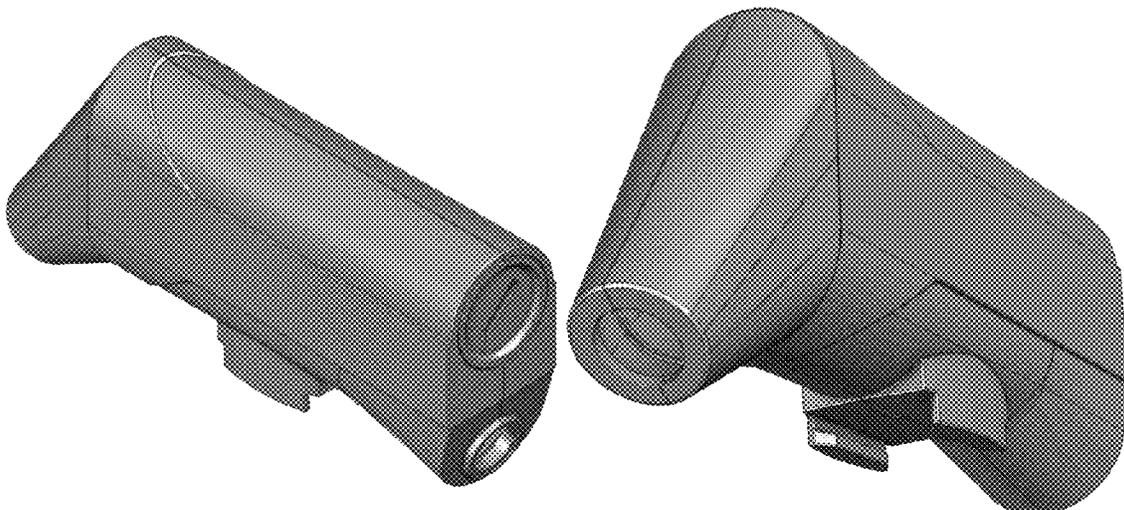
FIG. 11 is a bottom-right front view of the probe head of FIG. 1.

FIG. 12 is a bottom-left front view of the probe head of FIG. 1.

FIG. 13 is a bottom-left rear view of the probe head of FIG. 1; and,

FIG. 14 is a bottom-right rear view of the probe head of FIG. 1.

1 Claim, 14 Drawing Sheets



(58) **Field of Classification Search**

CPC G01N 29/265; A61B 8/4455; A61B 8/445;
A61B 5/0095; A61B 8/4444; G01S
7/5208

See application file for complete search history.

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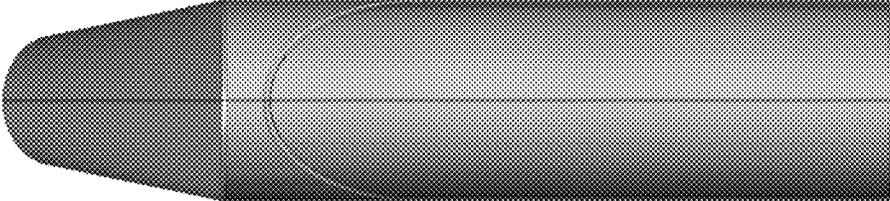


Fig. 1

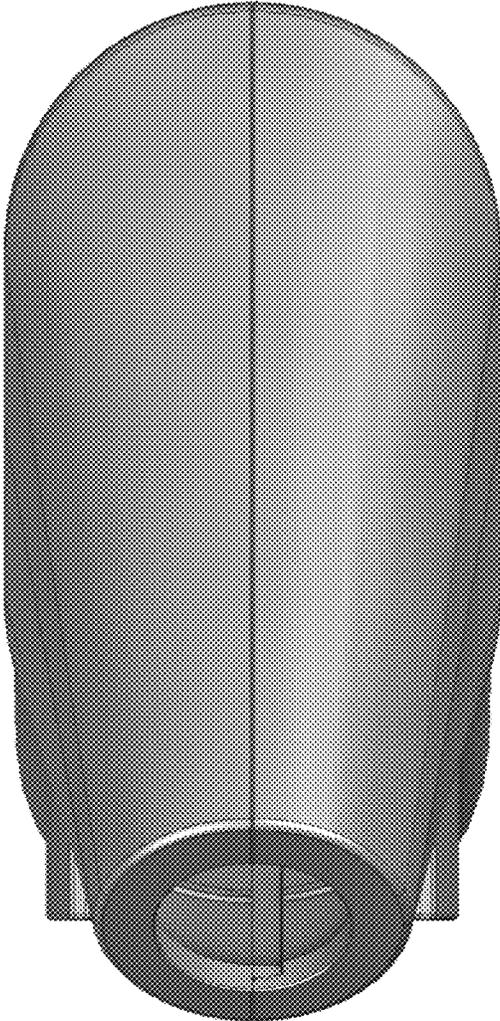


Fig. 2

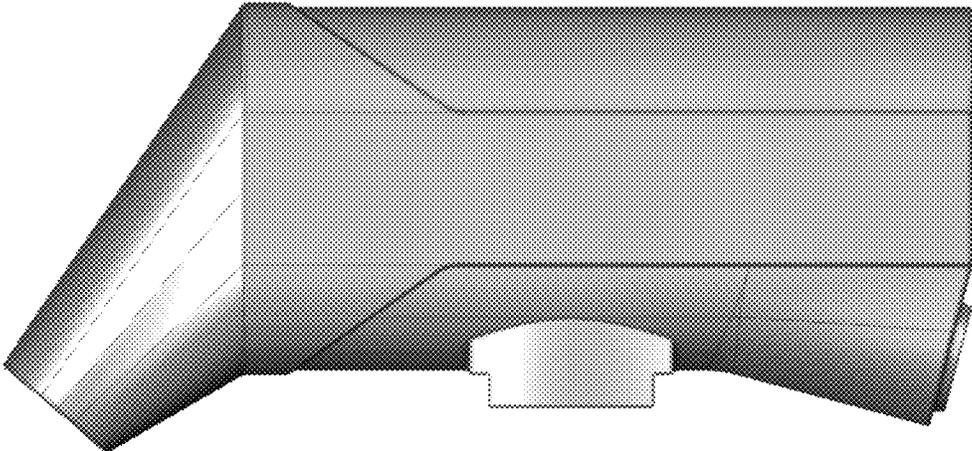


Fig. 3

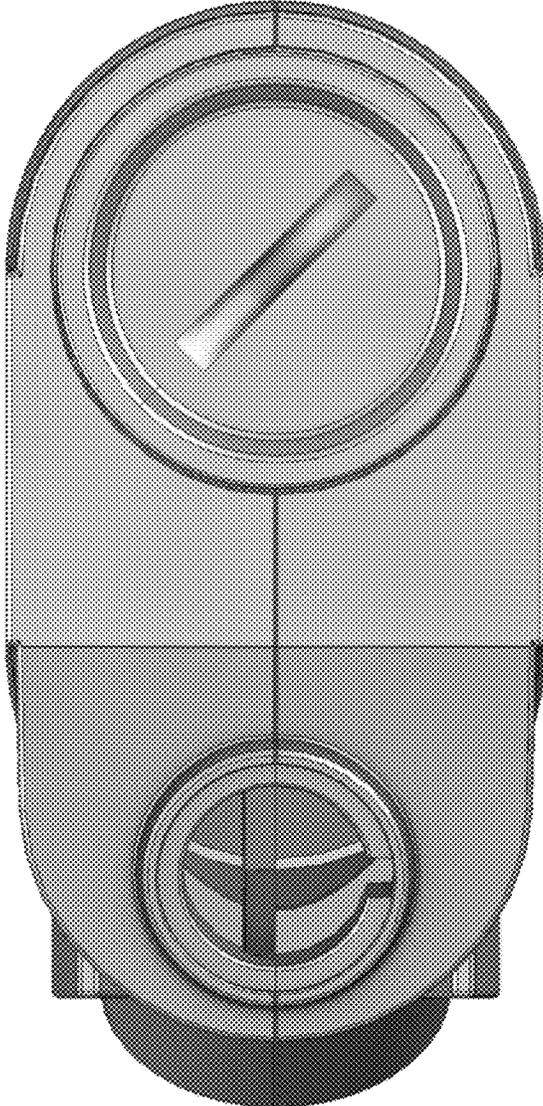


Fig. 4

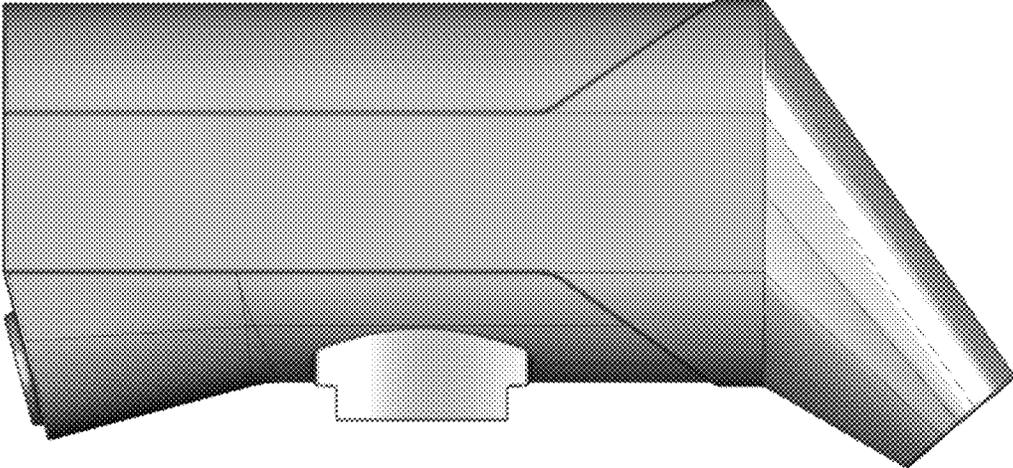


Fig. 5

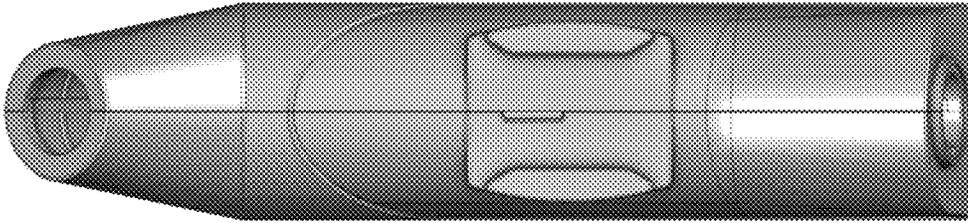


Fig. 6

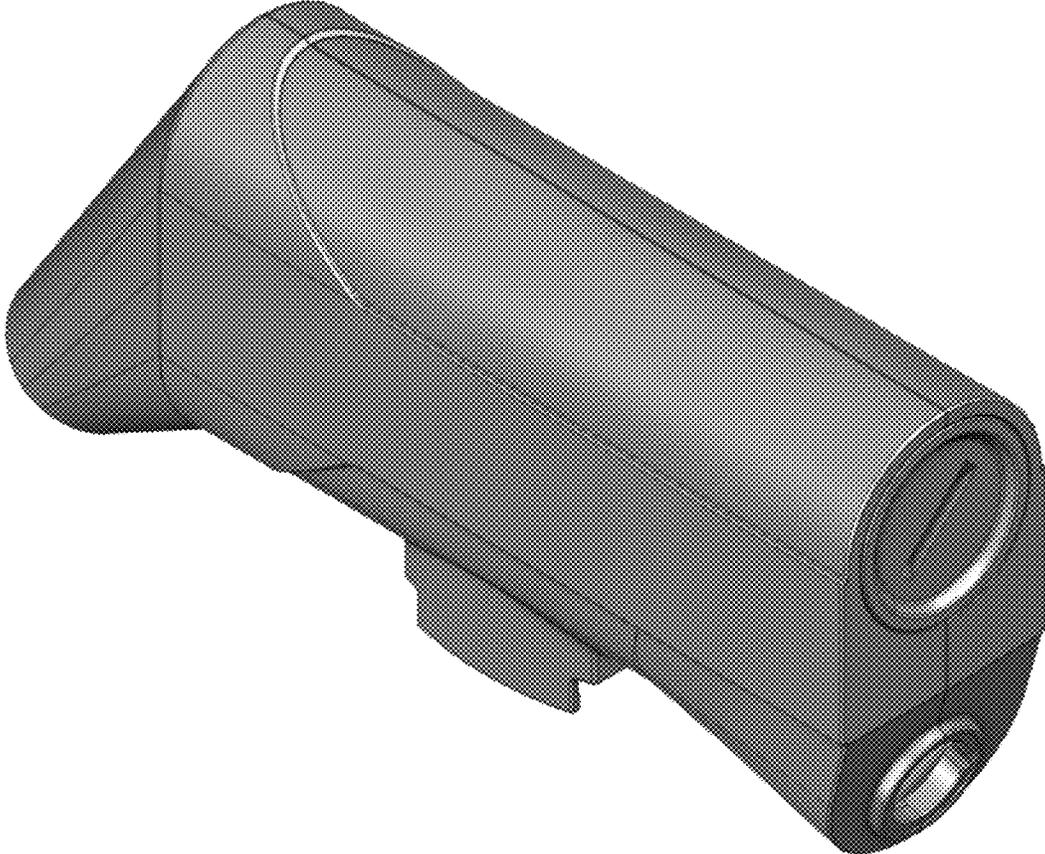


Fig. 7

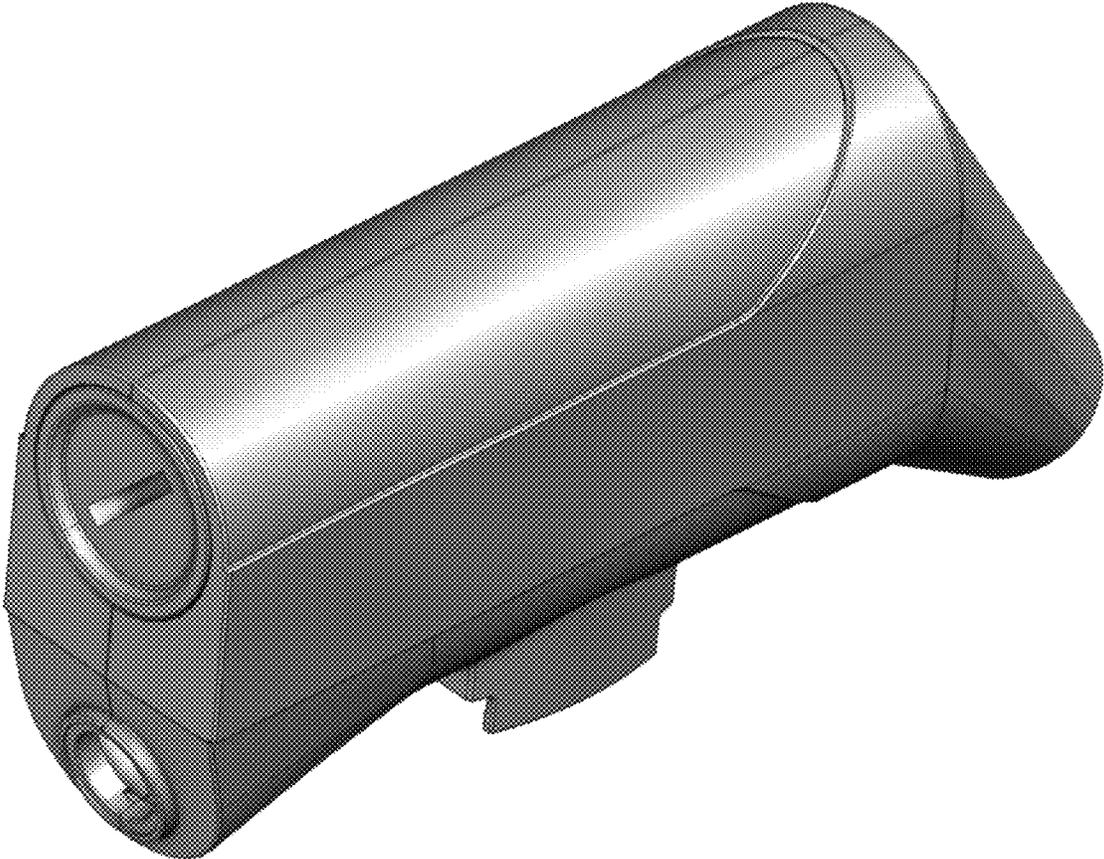


Fig. 8

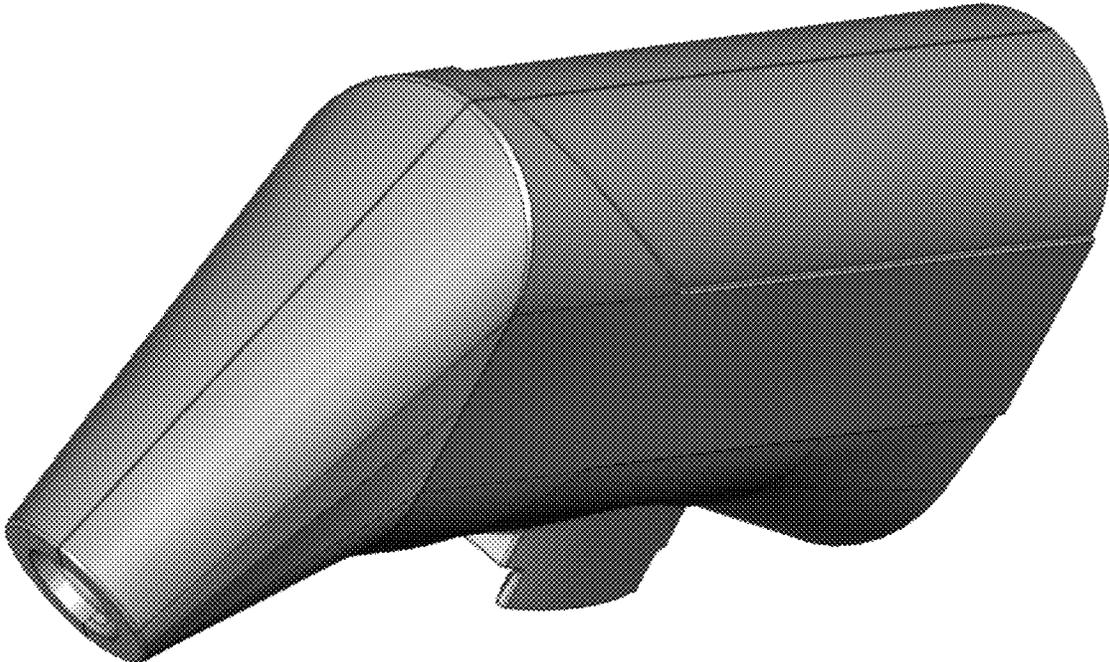


Fig. 9



Fig. 10

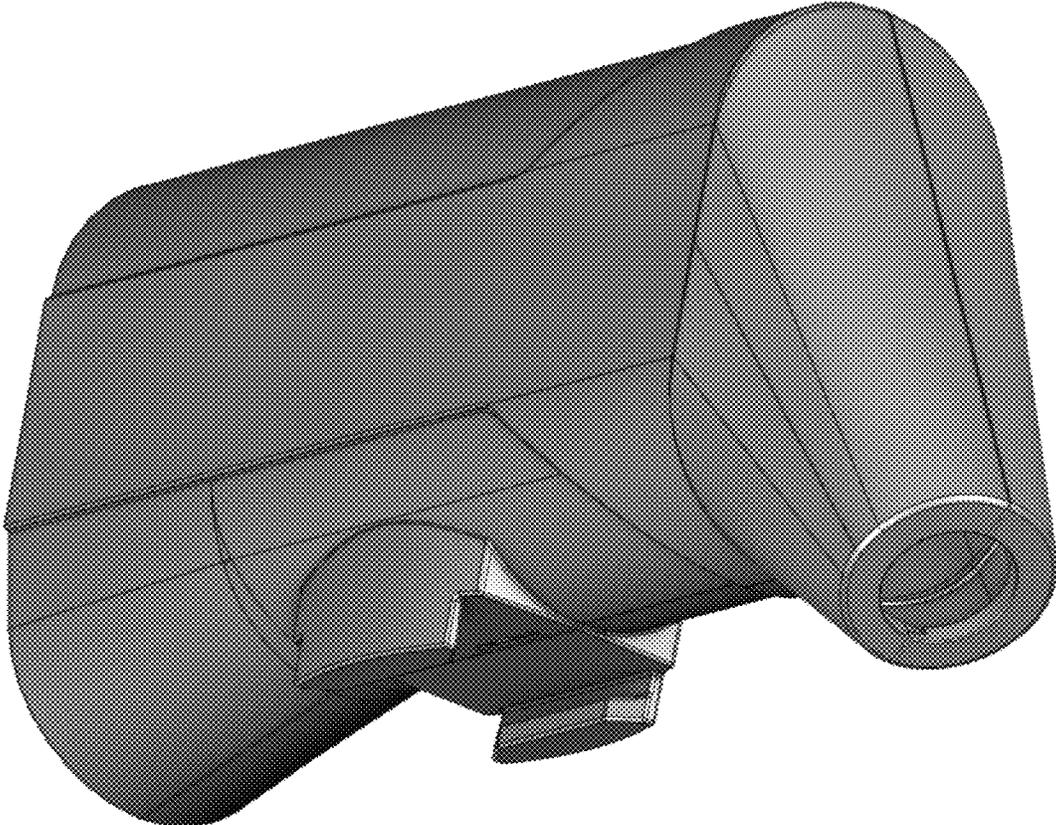


Fig. 11



Fig. 12

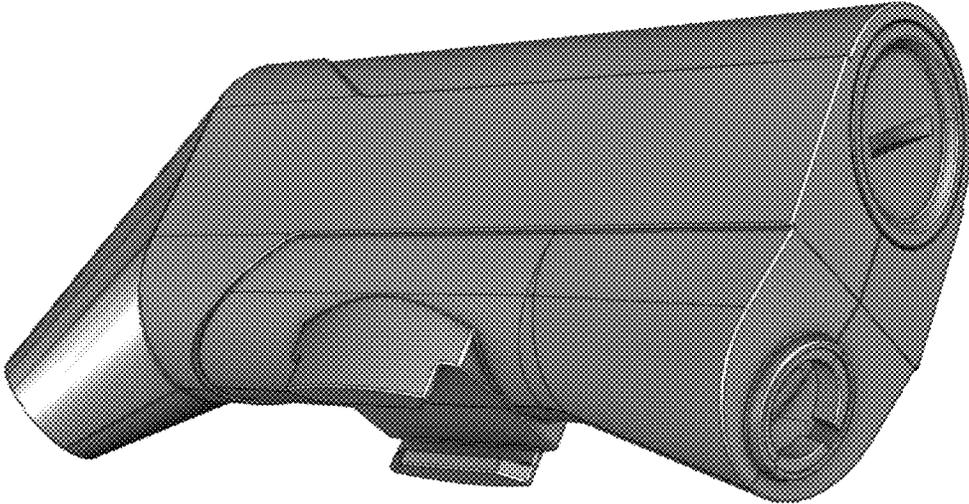


Fig. 13

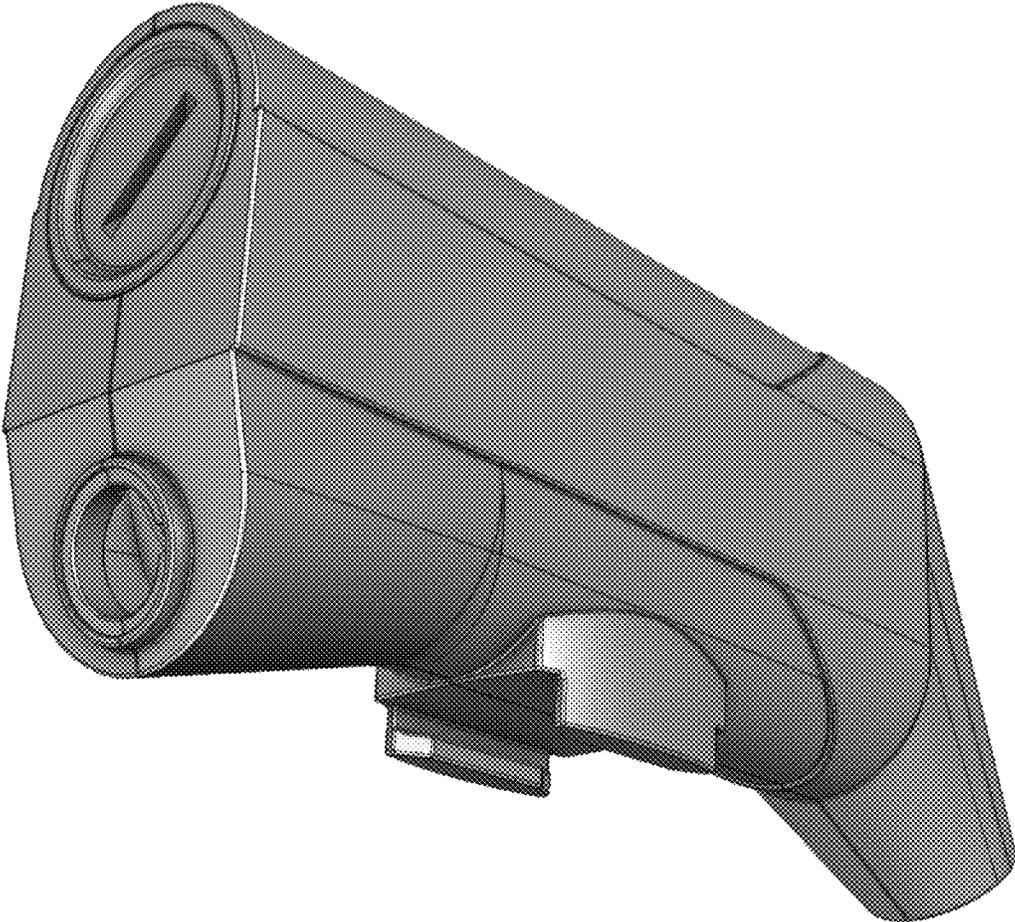


Fig. 14